

PRODUCT TECHNICAL BRIEF

KYKY EM-6900 Scanning Electron Microscope

KYKY EM-6900 Scanning Electron Microscope - LeakLab solutions for leak testing, vacuum systems and test equipment.

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Technical Data

PARAMETER	PUBLISHED VALUE / INFORMATION
SE resolution	3 nm at 30 kV
BSE resolution stated in the manufacturer brochure	6 nm at 30 kV
Magnification	8×-300,000× in the manufacturer brochure
Electron source	Pre-centered heated tungsten filament; LaB6 optional
Accelerating voltage	0-30 kV
Standard detectors listed	High-vacuum SE, four-segment semiconductor BSE and chamber camera
Stage	Motorized X/Y/Z/R with manual tilt; up to 175 mm specimen diameter
Vacuum system	Turbomolecular and rotary pumps
Options listed	EDS, EBSD, CL, EBL, heating/cooling stage, nanomanipulator and tensile stage

Technical and Project Information

Tungsten-filament scanning electron microscope for routine high-vacuum imaging, with LaB6 option. KYKY specifies 3 nm SE resolution at 30 kV, magnification to 300,000× and a motorized four-axis stage.

The EM-6900 is a conventional high-vacuum SEM for surface morphology, dimensional inspection and materials analysis. A low-vacuum EM-6900LV variant has also been produced; availability and specifications must be checked separately.

The former page mixed EM-6900 and EM-6910 terminology and made jurisdiction-specific metrology claims. Confirm the exact current model, guaranteed resolution, measurement software, calibration artifact, installation conditions and acceptance protocol in the quotation.

- Helium Reference Leaks
- Scanning Electron Microscopes
- Leak-Detector Accessories

WORLDWIDE PROJECT CONTACT

Send the test object or system, operating conditions, target sensitivity or pressure range, applicable standard, destination country, quantity and schedule. LeakLab will review the project scope.

mail@leaklab.org

Regarding: KYKY EM-6900 Scanning Electron Microscope

Specifications, standards, verification scope, availability and commercial terms must be confirmed for the exact configuration and destination jurisdiction before order or project acceptance.